

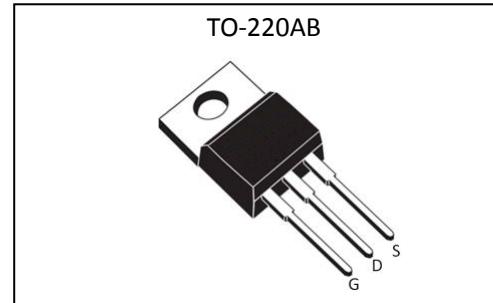
**Silicon N-Channel Power MOSFET****General Description :**

The HMB540 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications. The package form is TO-220AB, which accords with the RoHS standard.

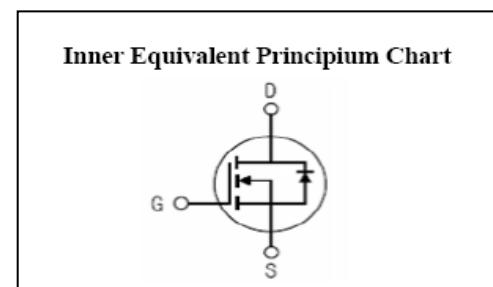
$V_{DSS}$	100	V
$I_D$	30	A
$P_D$	75	W
$R_{DS(ON)}\text{type}$	26	$\text{m}\Omega$

**Features :**

- $R_{DS(ON)} < 31\text{m}\Omega$  @  $V_{GS}=10\text{V}$  (Typ26mΩ)
- High density cell design for ultra low  $R_{dson}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

**Applications :**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

**Absolute (  $T_c = 25^\circ\text{C}$  unless otherwise specified ) :**

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	100	V
$I_D$	Continuous Drain Current	30	A
$I_{DM}$	Pulsed Drain Current	70	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$P_D$	Power Dissipation	75	W
$E_{AS}$	Single pulse avalanche energy <sup>a5</sup>	250	mJ
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	175, -55 to 175	°C

**Electrical Characteristics ( T<sub>C</sub> = 25°C unless otherwise specified ) :**

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	100	--	--	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> =100V, V <sub>GS</sub> = 0V, T <sub>a</sub> =25°C	--	--	1.0	μA
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> =+20V	--	--	0.1	μA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> =-20V	--	--	-0.1	μA

ON Characteristics <sup>a3</sup>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DSON</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =10A	--	26	31	mΩ
V <sub>GTH</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.3	--	2.5	V

Pulse width tp≤380μs, δ≤2%

Dynamic Characteristics <sup>a4</sup>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =10A	--	15	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V	--	2000	--	pF
C <sub>oss</sub>	Output Capacitance	f=1.0MHz	--	300	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	250	--	

Resistive Switching Characteristics <sup>a4</sup>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DD</sub> =50V, R <sub>L</sub> =5Ω	--	7	--	ns
t <sub>r</sub>	Rise Time		--	7	--	
t <sub>d(OFF)</sub>	Turn-Off Delay Time		--	29	--	
t <sub>f</sub>	Fall Time		--	7	--	
Q <sub>g</sub>	Total Gate Charge	V <sub>DD</sub> =50V, I <sub>D</sub> =10A	--	39	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	8	--	
Q <sub>gd</sub>	Gate to Drain ( "Miller" )Charge		--	12	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current <sup>a2</sup> (Body Diode)		--	--	30	A
$V_{SD}$	Diode Forward Voltage <sup>a3</sup>	$I_S=30A, V_{GS}=0V$	--	--	1.2	V
$t_{rr}$	Reverse recovery time	$IF=30,$ $dI/dt=100A/\mu s$		35		ns
$Q_{rr}$	Reverse recovery charge			58		nC

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case <sup>a2</sup>	2	°C/W
$R_{\theta JA}$	Junction-to-Ambient	62	

<sup>a1</sup> : Repetitive Rating: Pulse width limited by maximum junction temperature.

<sup>a2</sup> : Surface Mounted on FR4 Board,  $t \leq 10\text{sec}$ .

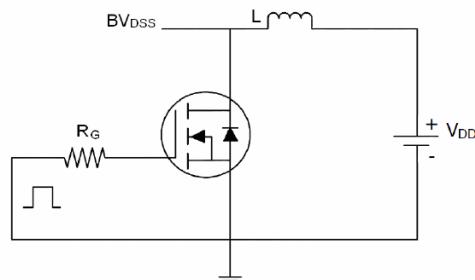
<sup>a3</sup> : Pulse Test: Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 2\%$ .

<sup>a4</sup> : Guaranteed by design, not subject to production

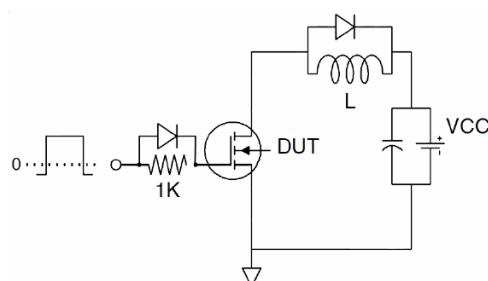
<sup>a5</sup> : EAS condition :  $T_j=25^\circ\text{C}, V_{DD}=35\text{V}, V_G=10\text{V}, L=0.5\text{mH}, R_g=25\Omega$

**Test circuit**

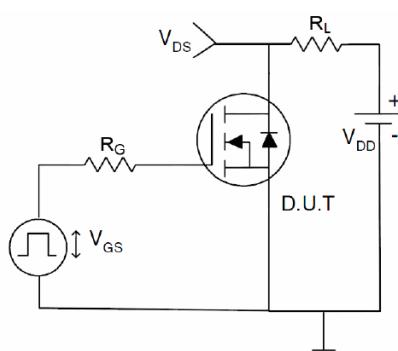
1) EAS test Circuit

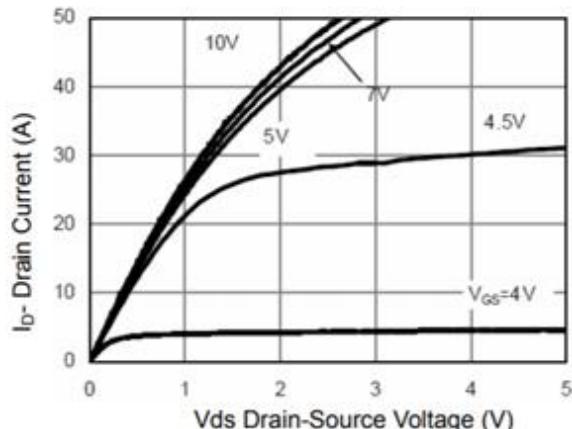
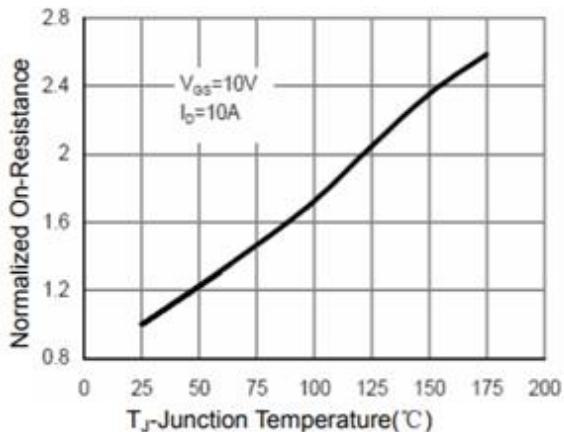
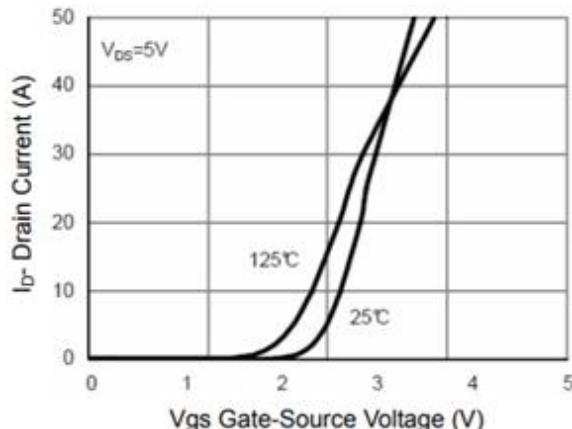
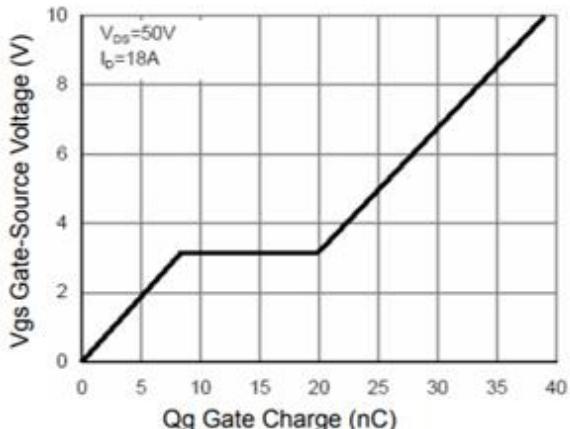
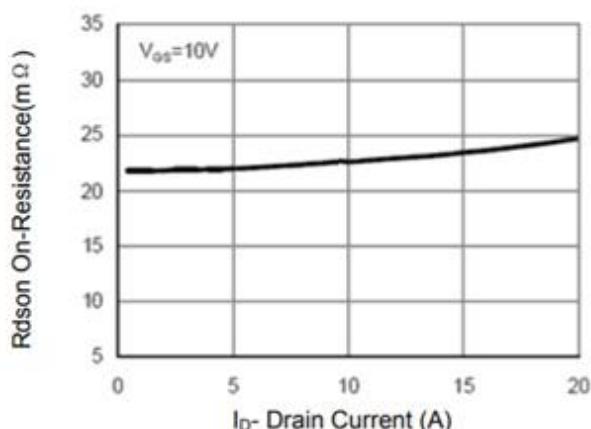
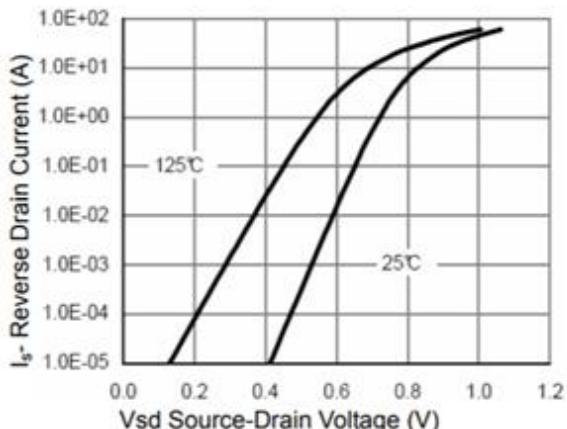


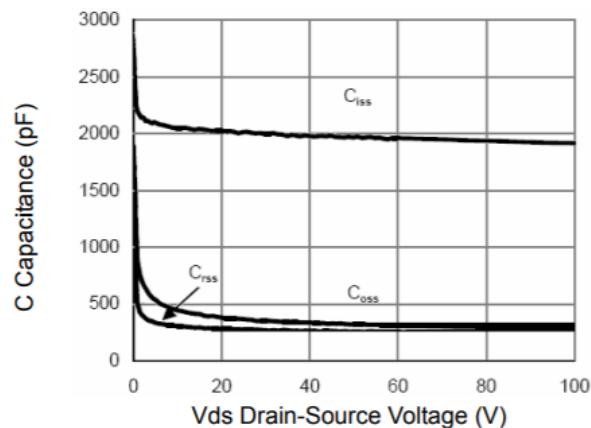
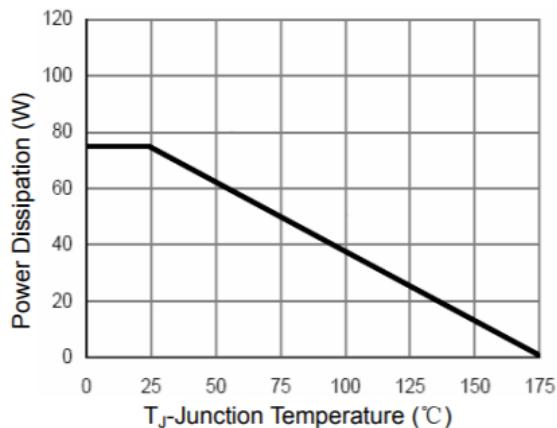
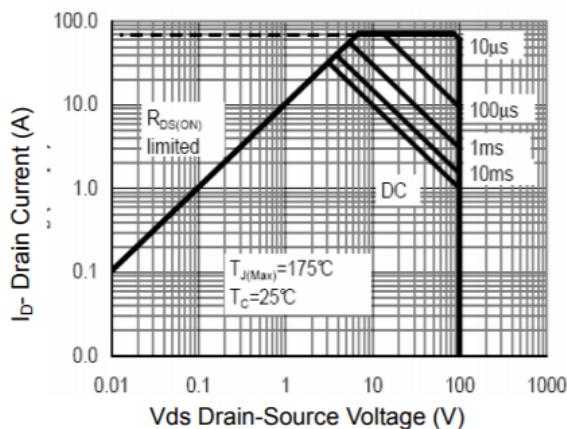
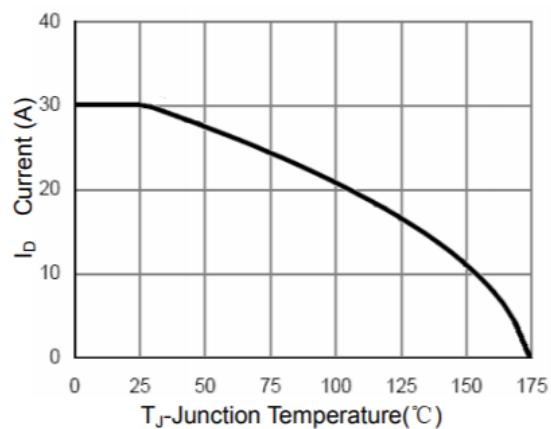
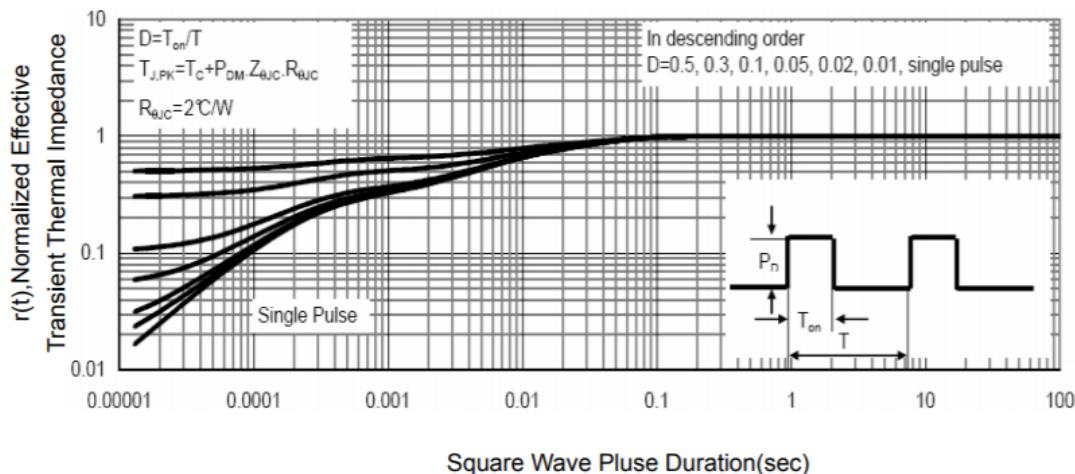
2) Gate charge test Circuit



3) Switch Time Test Circuit



**Typical Electrical and Thermal Characteristics (Curves)**

**Figure 1 Output Characteristics**

**Figure 4 Rdson-JunctionTemperature**

**Figure 2 Transfer Characteristics**

**Figure 5 Gate Charge**

**Figure 3 Rdson- Drain Current**

**Figure 6 Source- Drain Diode Forward**


**Figure 7 Capacitance vs Vds**

**Figure 9 Power De-rating**

**Figure 8 Safe Operation Area**

**Figure 10ID Current- Junction Temperature**

**Figure 11 Normalized Maximum Transient Thermal Impedance**